

Recent Results of CERN RD39 Collaboration on Development of Radiation Hard Si Detectors Operated at Low to Cryogenic Temperatures

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On behalf of CERN RD 39 Collaboration

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Outline

1. The CID (Current-Injected-Diode) Concept and Principle
2. Test Results of CID Strip Detectors
3. CID Application for LHC Beam-Loss-Monitor
4. Summary

Effect of Trapping on CCE in sLHC

Trapping effect on CCE in LHC Upgrade

$$Q = Q_0 \cdot CCE = Q_0 \cdot \frac{w}{d} \cdot \frac{\tau_t}{t_{dr}} (1 - e^{-t_{dr}/\tau_t})$$

Trapping term

Depletion term

For fluence 10^{16} n/cm², the trapping term CCE_+ is a limiting factor of detector operation!

For sLHC fluences :

$$Q \cong 80 \text{ e' s}/\mu\text{m} \cdot v_{dr} \cdot \tau_t \cong 80 \cdot d_t \text{ (e' s)}$$

$d_t = v_{dr} \cdot \tau_t$ is the trapping distance

Effect of Trapping on CCE in SLHC

TRAPPING

$$\tau_t = \frac{1}{\sigma v_{th} N_{t,empty}}$$

The thermal velocity $v_{th} \approx 10^7$ cm/s

10^{16} cm⁻² irradiation produces $N_{t,empty} \approx 3-5 \cdot 10^{16}$ cm⁻³ with $\sigma \approx 10^{-14}$ cm²

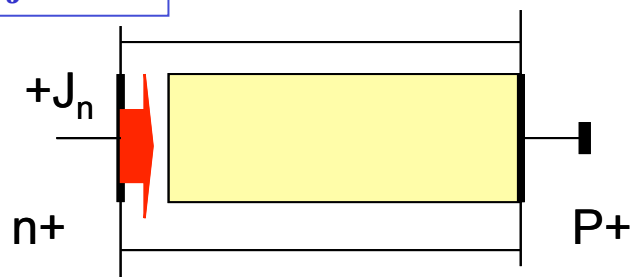
On average (e and h) it gives a $\tau_t \approx 0.2$ ns!

Even in highest E-field (Saturation velocity, 10^7 cm/s), carrier drifts only 20-30 μ m before it gets trapped regardless whether the detector is fully depleted or not !

In S-LHC conditions, about 90% of the volume of $d=300\mu$ m detector is dead space if $N_{t,empty}$ is not reduced!

The CID Concept and Principle (CERN RD 39 Collaboration)

Carrier injection



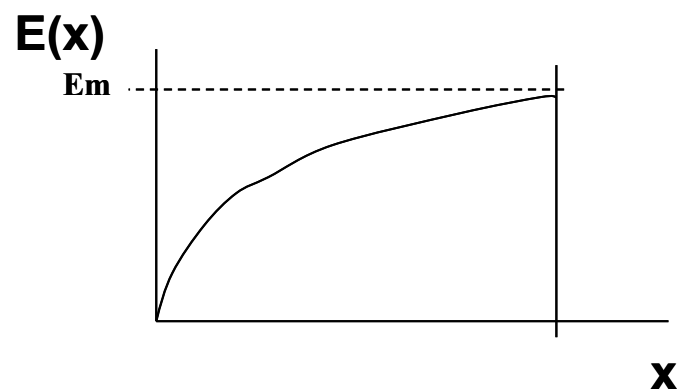
$$J_n = en\mu E$$

$$\text{div}J=0$$

$$\text{div}E=n_{tr}$$

$$E(x=0) = 0$$

(SCLC: Space Charge Limited Current mode)



$$E(x) = \frac{3V}{2d} \cdot \sqrt{\frac{x}{d}} \quad E_m = \frac{3}{2} \cdot \frac{V}{d}$$

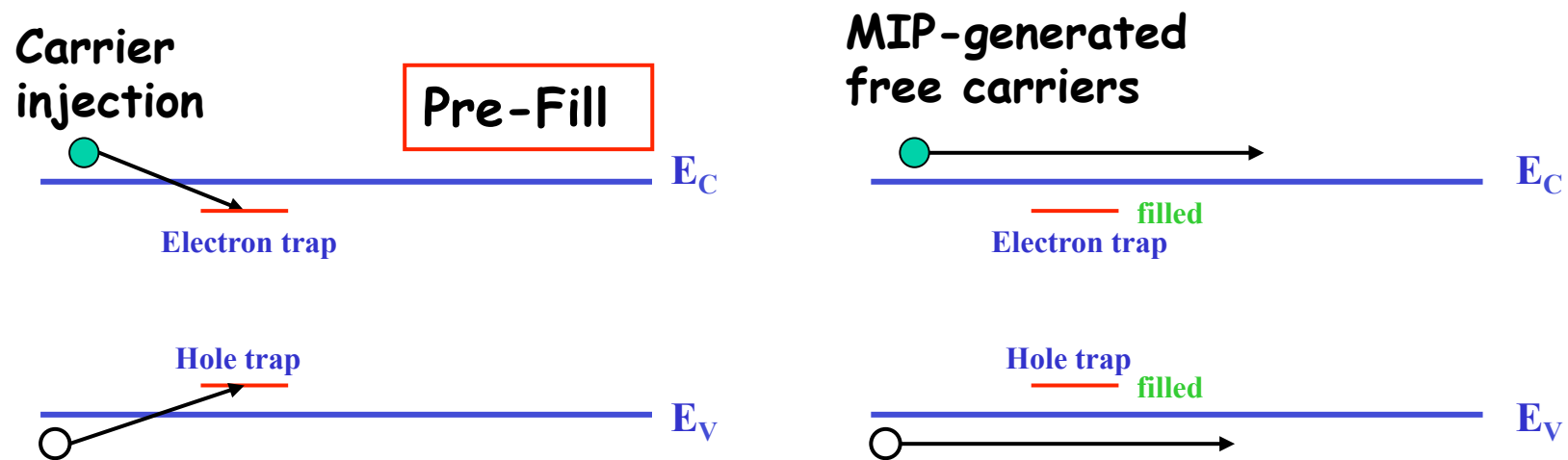
The key advantage:

The shape of $E(x)$ is **not affected** by fluence, and **virtual full depletion**

The CID Concept and Principle

Pre-filling of traps by carrier injection

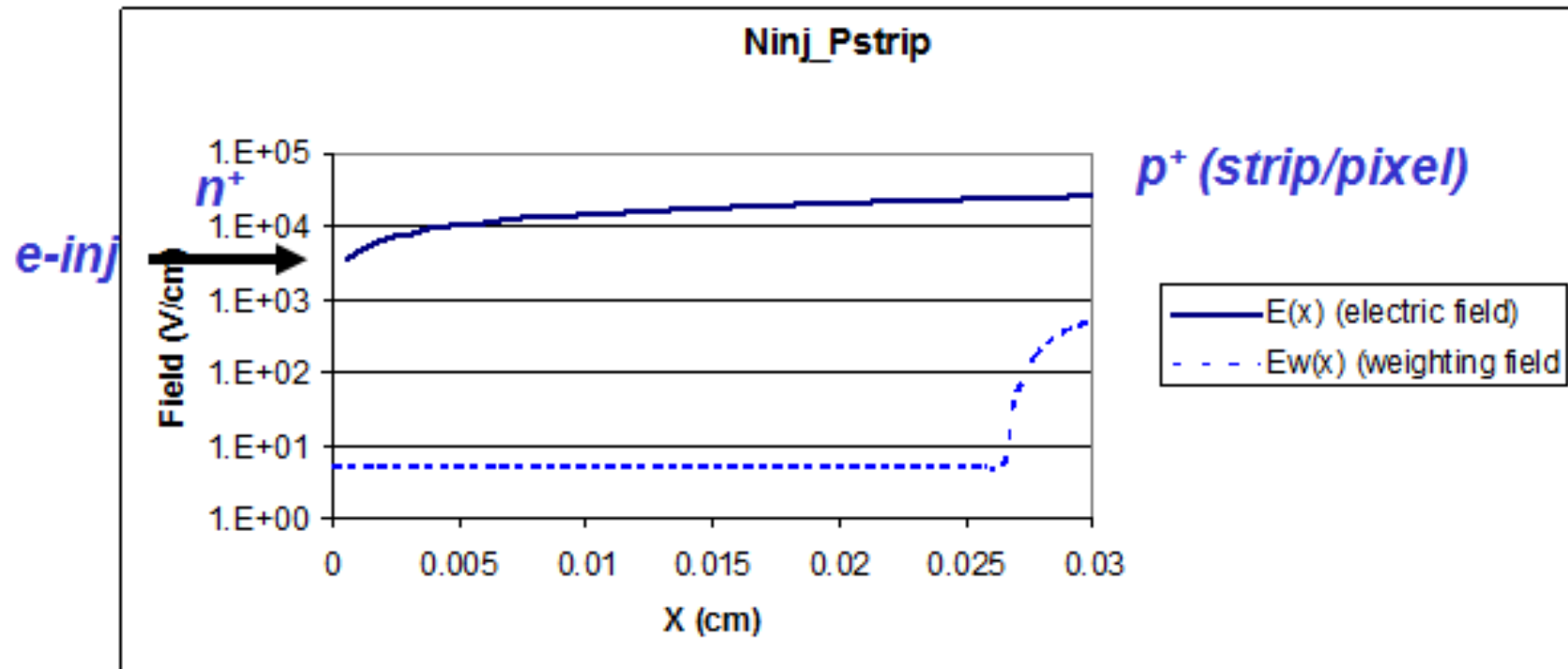
Carrier injection can also pre-fill the traps to make them inactive

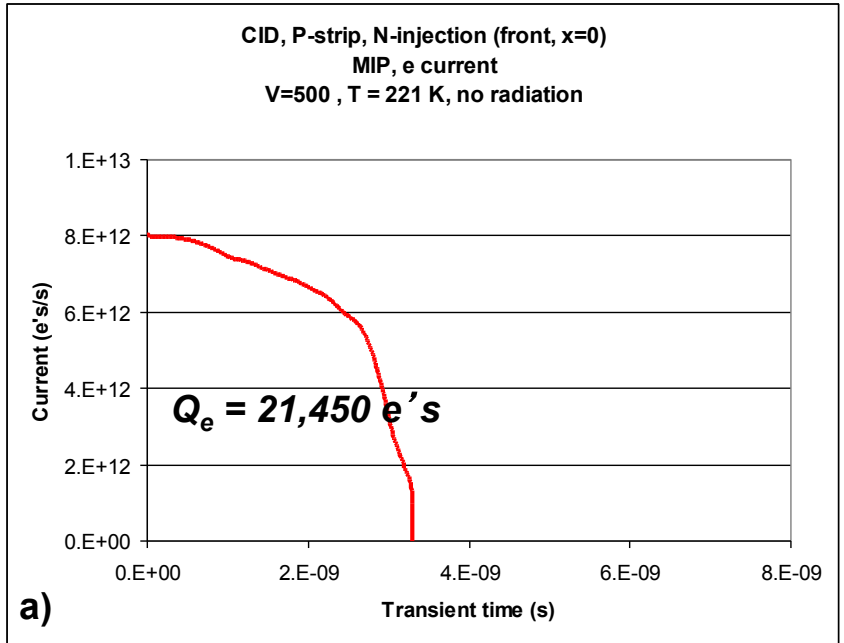


$$N_{t,empty} \downarrow \longrightarrow \tau_t \uparrow \longrightarrow Q \uparrow$$

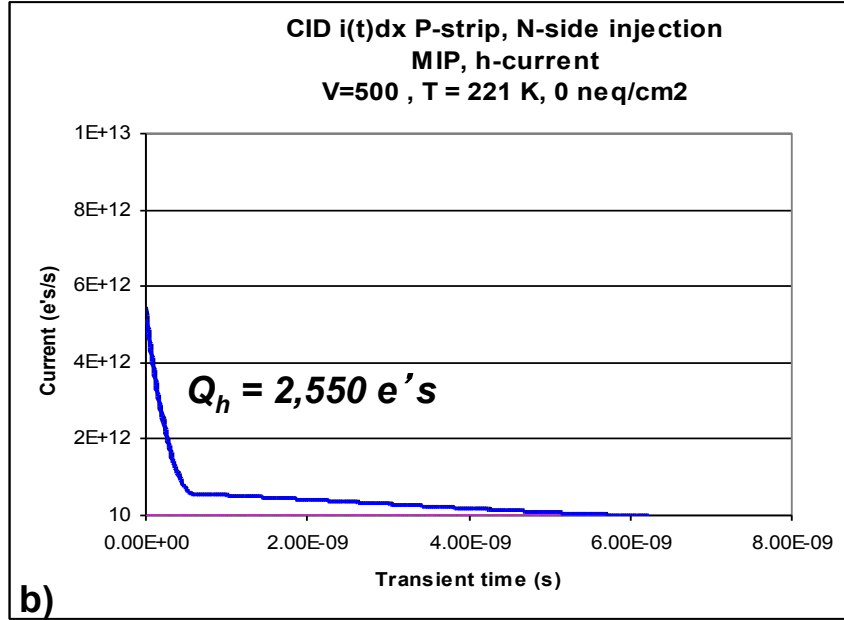
CID Simulation

$V = 500 \text{ V}$, $T = 221 \text{ K}$





No radiation
Q = 24,000 e's
(89.4% by electrons)



CID Simulation

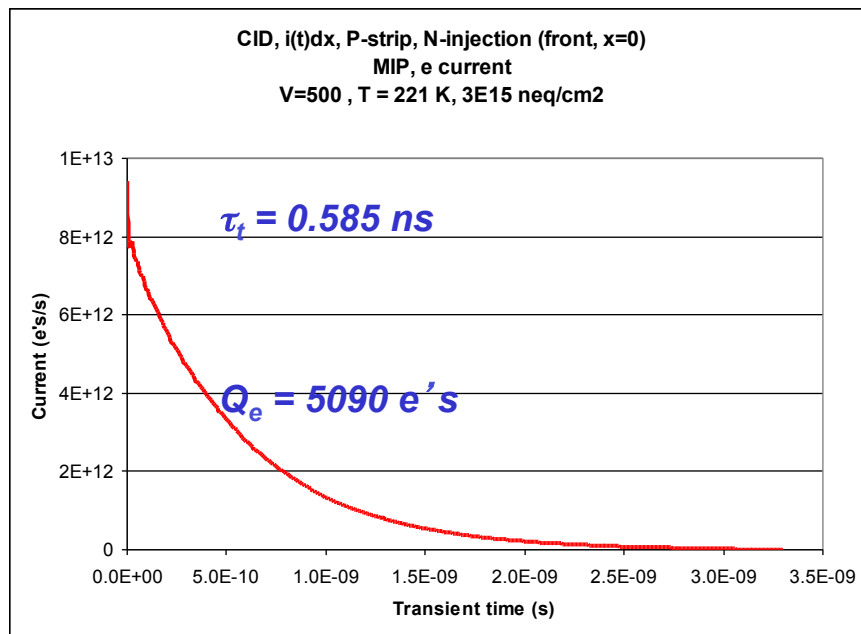
$V = 500 \text{ V}, T = 221 \text{ K}$

Standard Strip Detector

$$3 \times 10^{15} n_{eq}/\text{cm}^2$$

$$Q = 6110 e's$$

(83% by electrons)

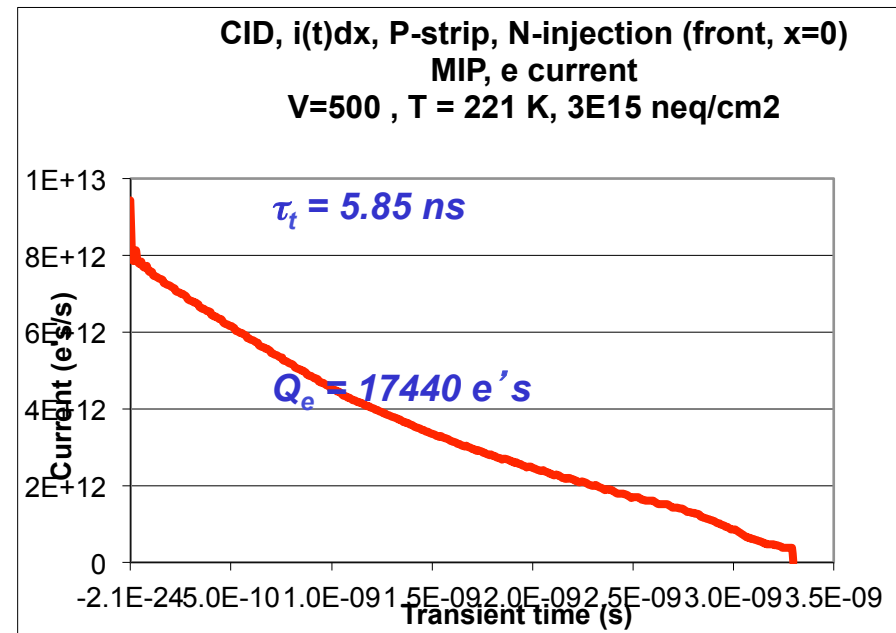


CID Strip Detector

$$3 \times 10^{15} n_{eq}/\text{cm}^2$$

$$Q = 18360 e's$$

(94% by electrons)



CID Simulation

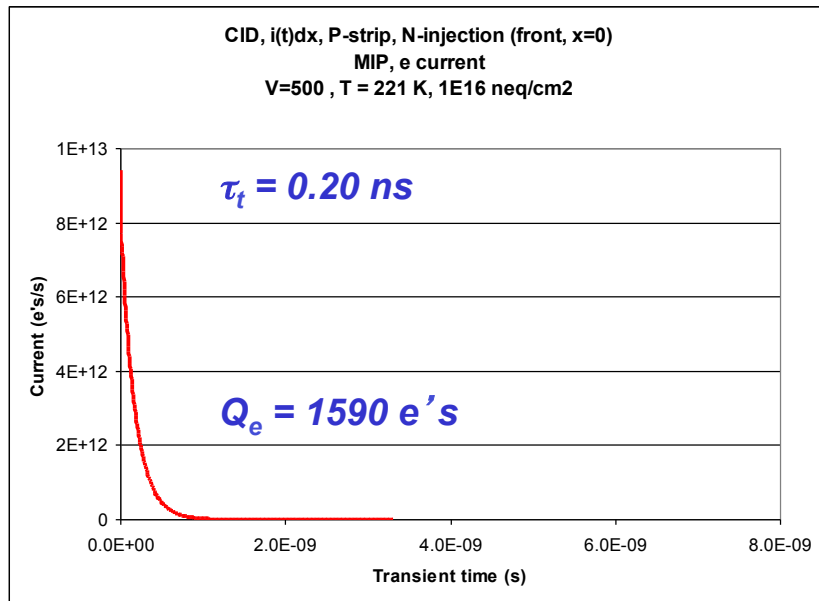
$V = 500 \text{ V}, T = 221 \text{ K}$

Standard Strip Detector

$1 \times 10^{16} n_{eq}/\text{cm}^2$

$Q = 2140 \text{ e}'s$

(74% by electrons)

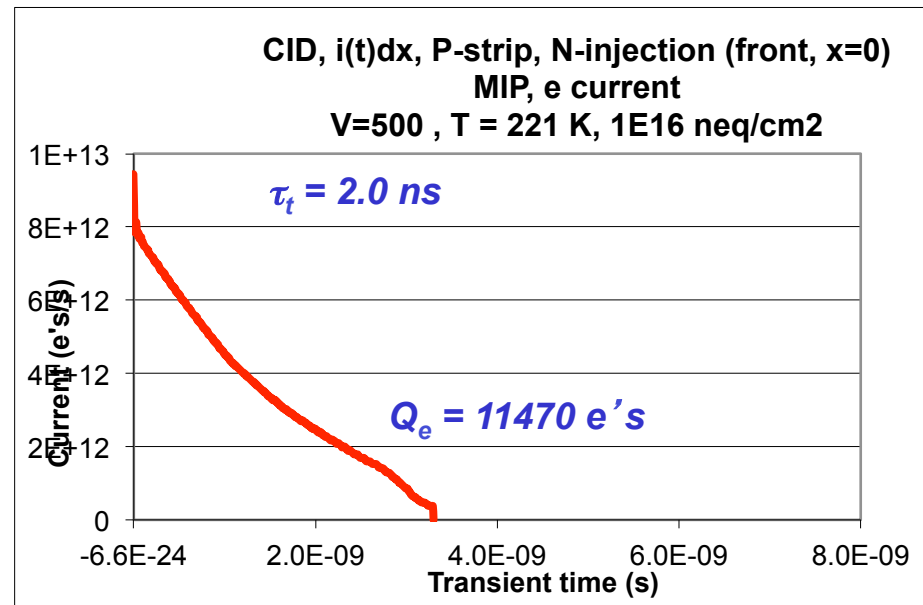


CID Strip Detector

$1 \times 10^{16} n_{eq}/\text{cm}^2$

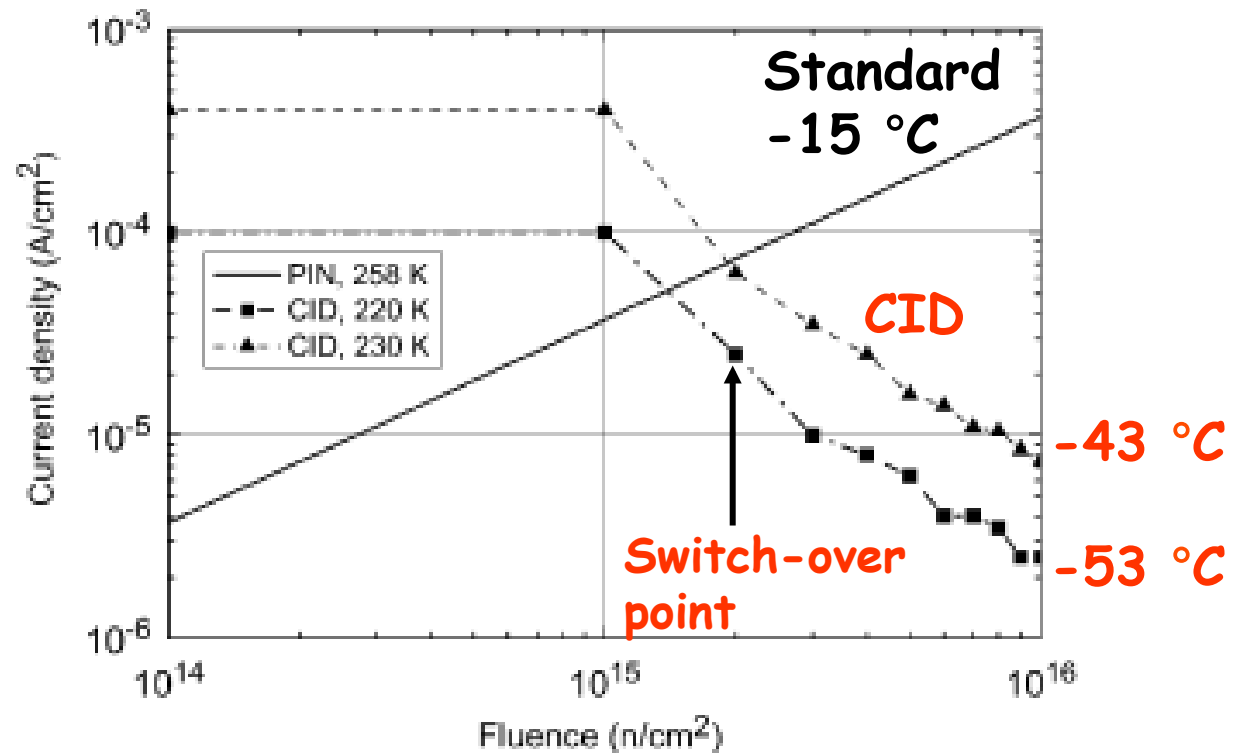
$Q = 12020 \text{ e}'s$

(94% by electrons)

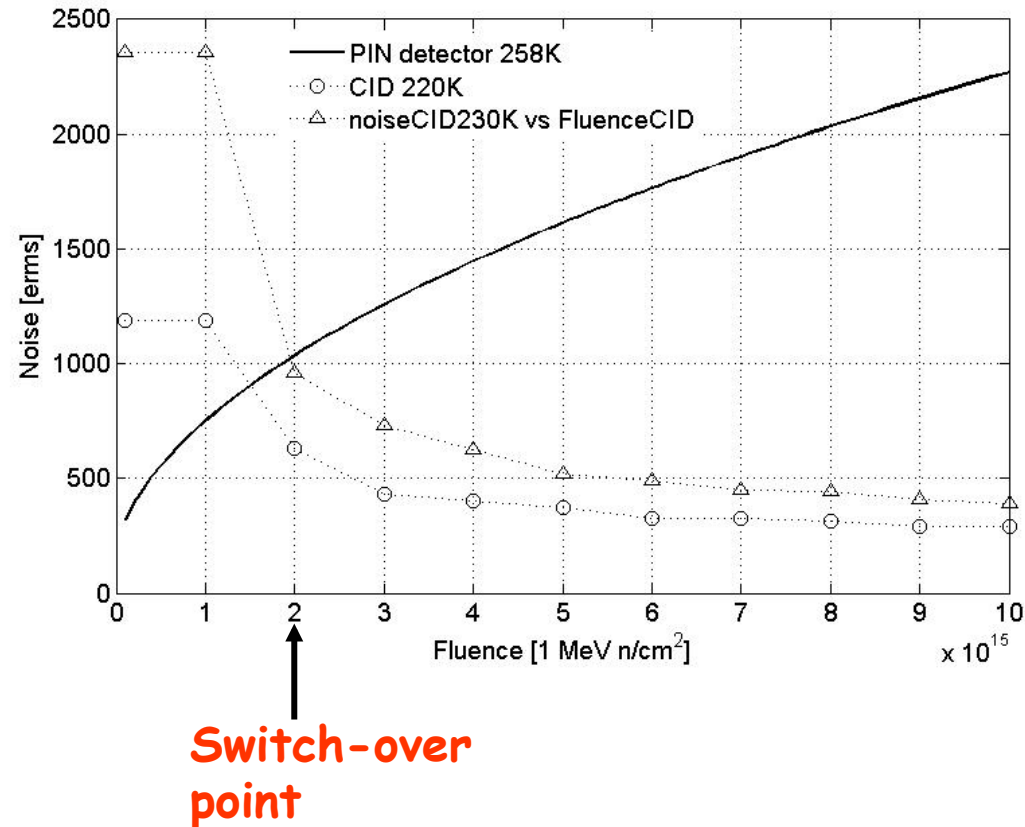


Current comparisons

Switch over point from standard reverse bias to CID
(forward) is $2 \times 10^{15} \text{ n}_{\text{eq}}/\text{cm}^2$



Simulation of noise performance of CID detector versus normal detector operation.

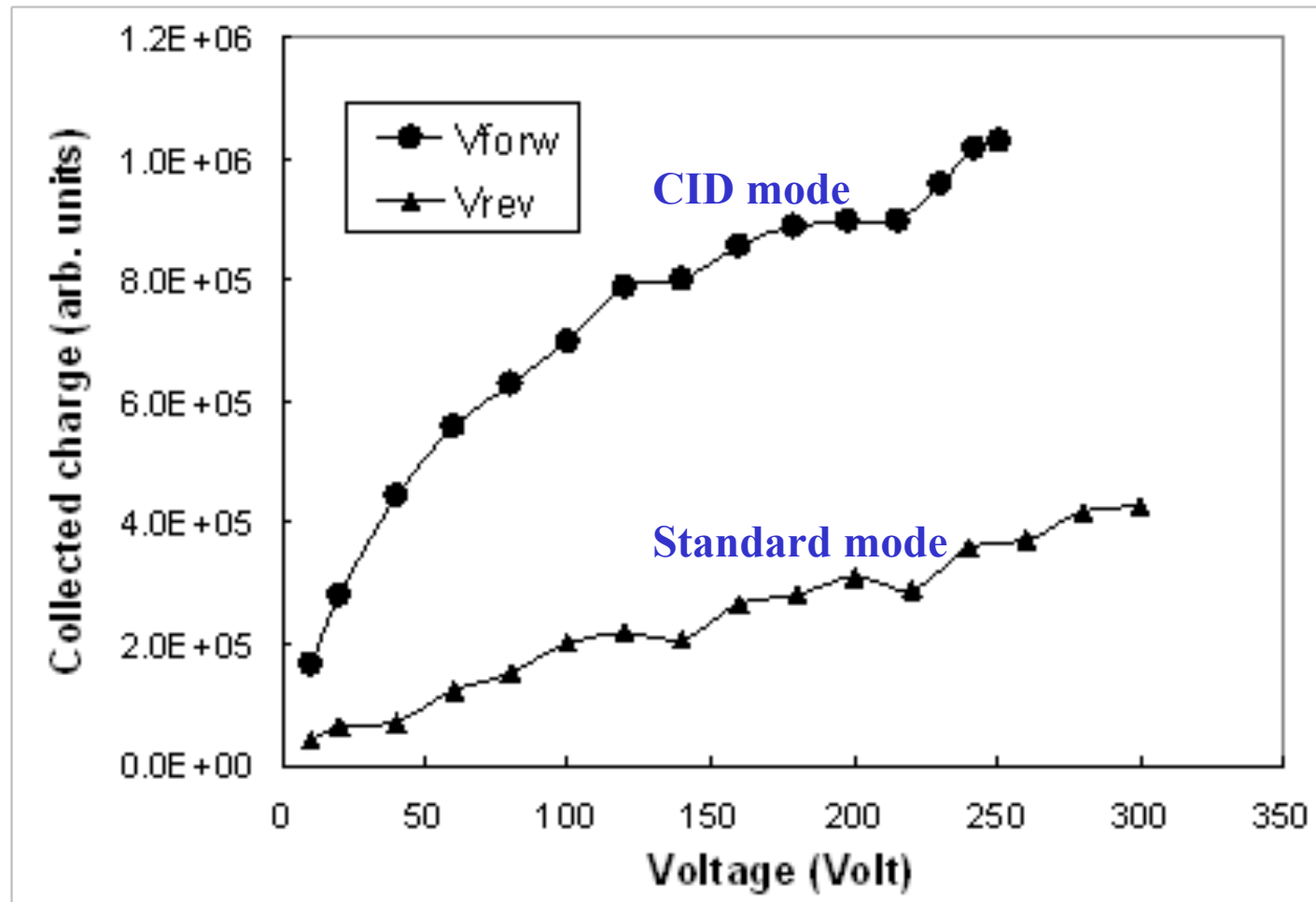


The simulation has been made according to the strip detector design of CERN ATLAS experiment: pitch 80 μm , strip length 6 cm and read-out shaping time 25 ns, PIN is biased to the full depletion and the temperature is 258 K. The bias for CID is 200V. As it can be seen, at fluence $2 \times 10^{15} \text{ n}_{\text{eq}}/\text{cm}^2$ the CID noise becomes lower than in PIN detector.

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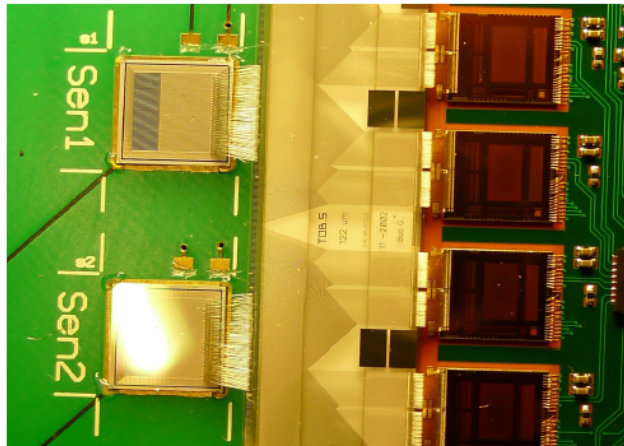
Test Results of CID Detectors

$\Phi_n = 1 \times 10^{15} \text{ cm}^{-2}$, $T = 180 \text{ K}$, MIPs (1050 nm laser)



Test Results of CID Strip Detectors

Test Beam set up



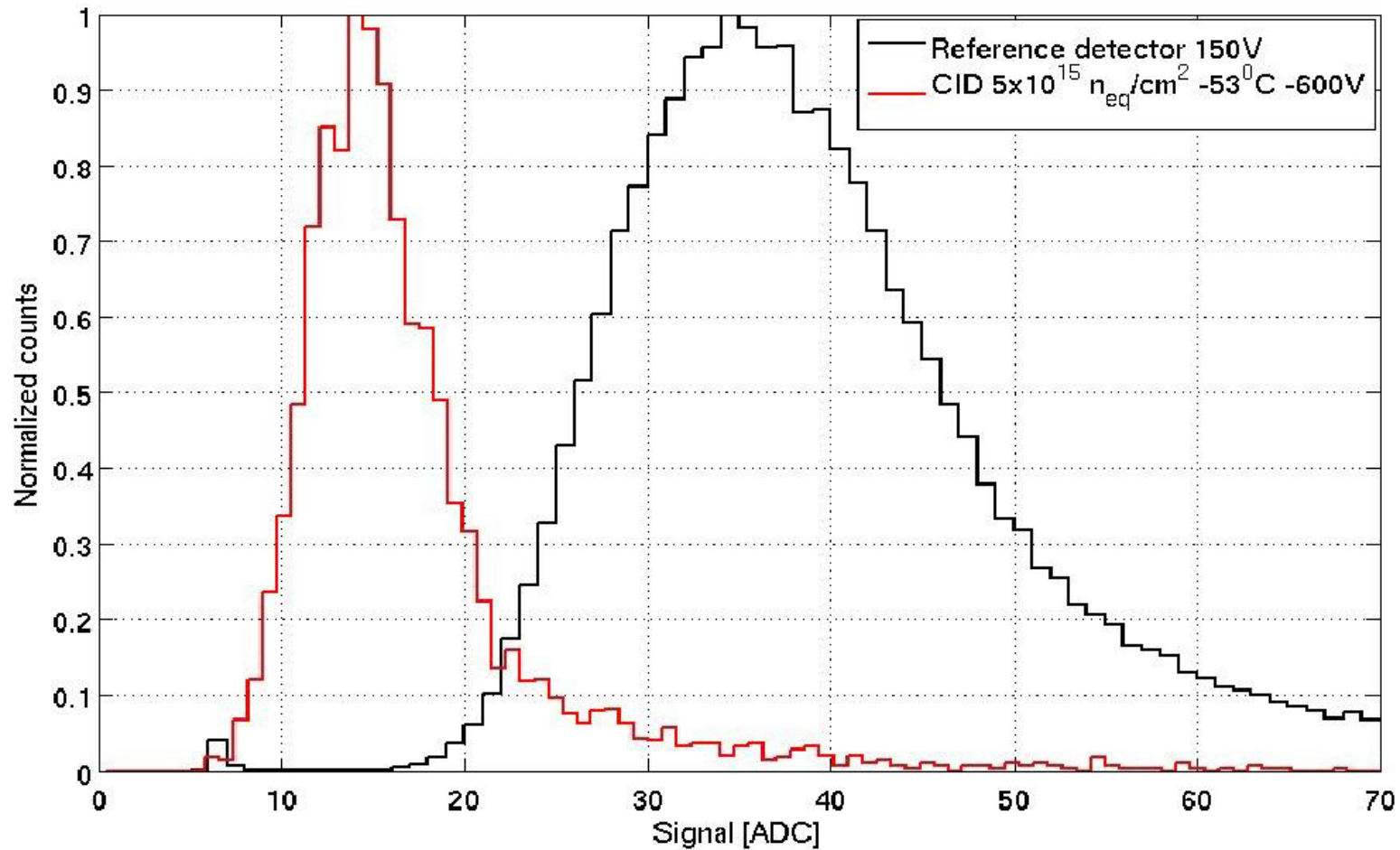
- CMS readout and DAQ
- Operated at CERN H2 area and FNAL
- Nominal resolution $4\mu\text{m}$, 10 reference planes, effective area $4\times 4\text{ cm}^2$.
- Detector module can be cooled $\approx -53^\circ\text{C}$ by Peltier elements
- Test beam setup gradually developed since past ≈ 10 yrs

Test Beam experiment on CID detectors 2008-2011

- Sensors investigated
 - $2\times 10^{15}\text{ n}_{\text{eq}}/\text{cm}^2\text{ n}^+/\text{p}^-/\text{p}^+$ MCz-Si
 - $5\times 10^{15}\text{ n}_{\text{eq}}/\text{cm}^2\text{ p}^+/\text{n}^-/\text{n}^+$ MCz-Si (in 2008 $3\times 10^{15}\text{ n}_{\text{eq}}/\text{cm}^2\text{ p}^+/\text{n}^-/\text{n}^+$ MCz-Si)

Test Results of CID Strip Detectors

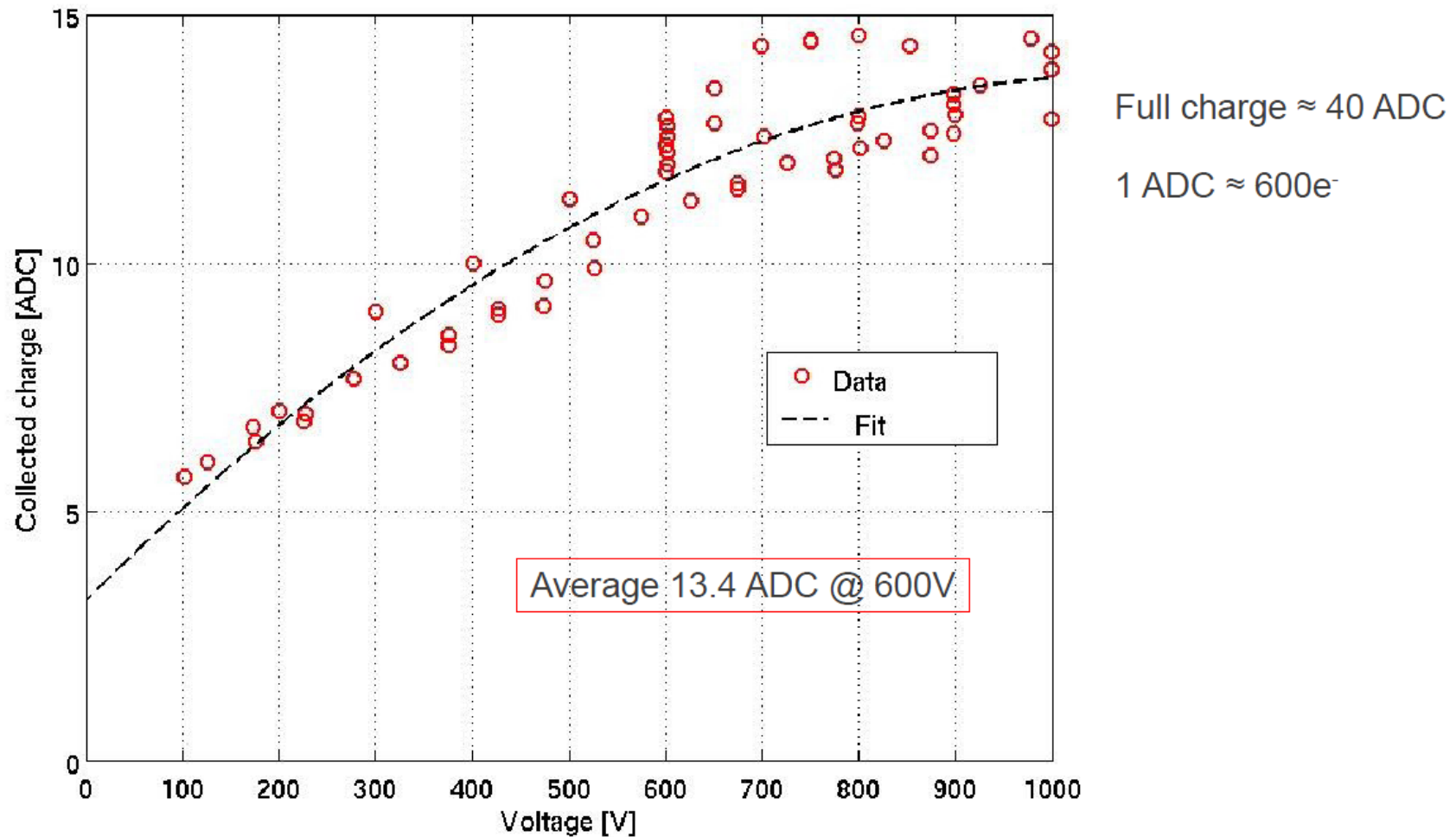
$5 \times 10^{15} \text{ n}_{\text{eq}}/\text{cm}^2$ results - Collected charge vs non-irrad



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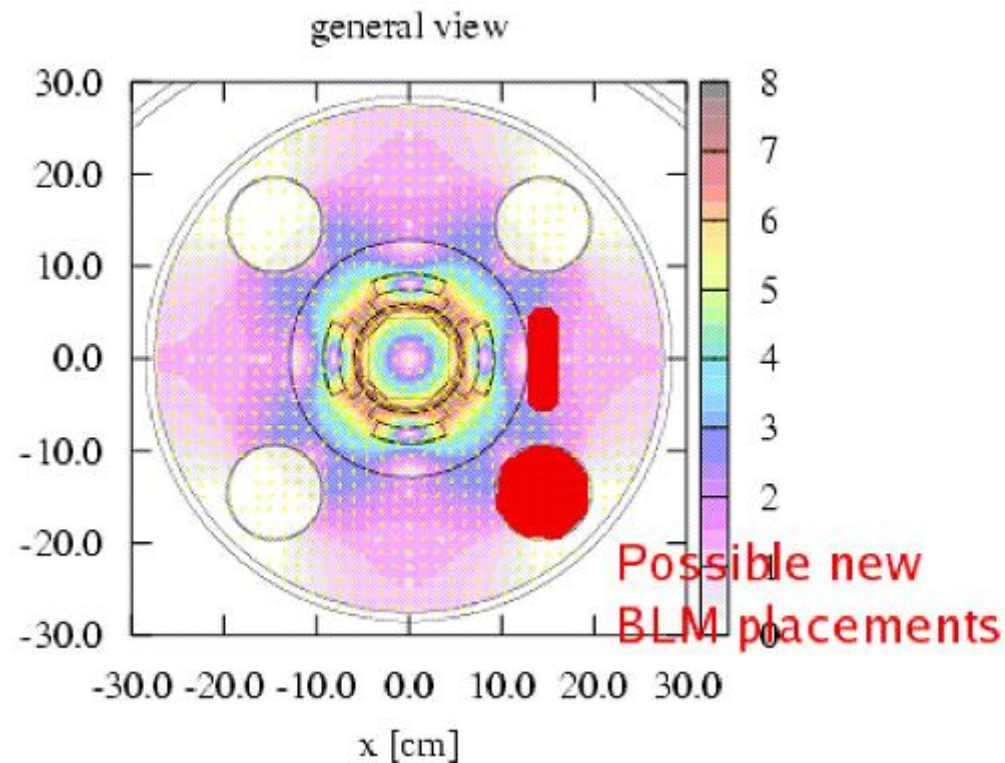
Test Results of CID Strip Detectors

$5 \times 10^{15} \text{ n}_{\text{e}}/\text{cm}^2$ results - Collected charge vs V CID mode



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CID Application for LHC Beam-Loss-Monitor



Current BLM placement

- LHC upgrade will require BLM to be located inside of LHe cryostat.
- BLM will receive radiation load comparable with S-LHC pixel sensors
- At 1.8K radiation defects will trap >50% of signal
- Polarization makes normal reverse bias operation impossible

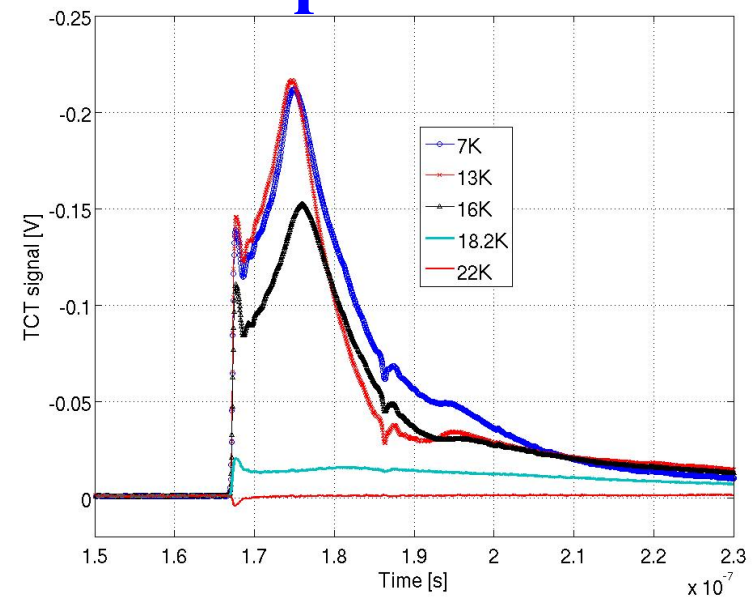
Laser Tests for LHC Beam-Loss-Monitor



Detector arrangement

**Crogenic TCT at CERN
with ps laser**

**Preliminary TCT data
CID operated at <25K**

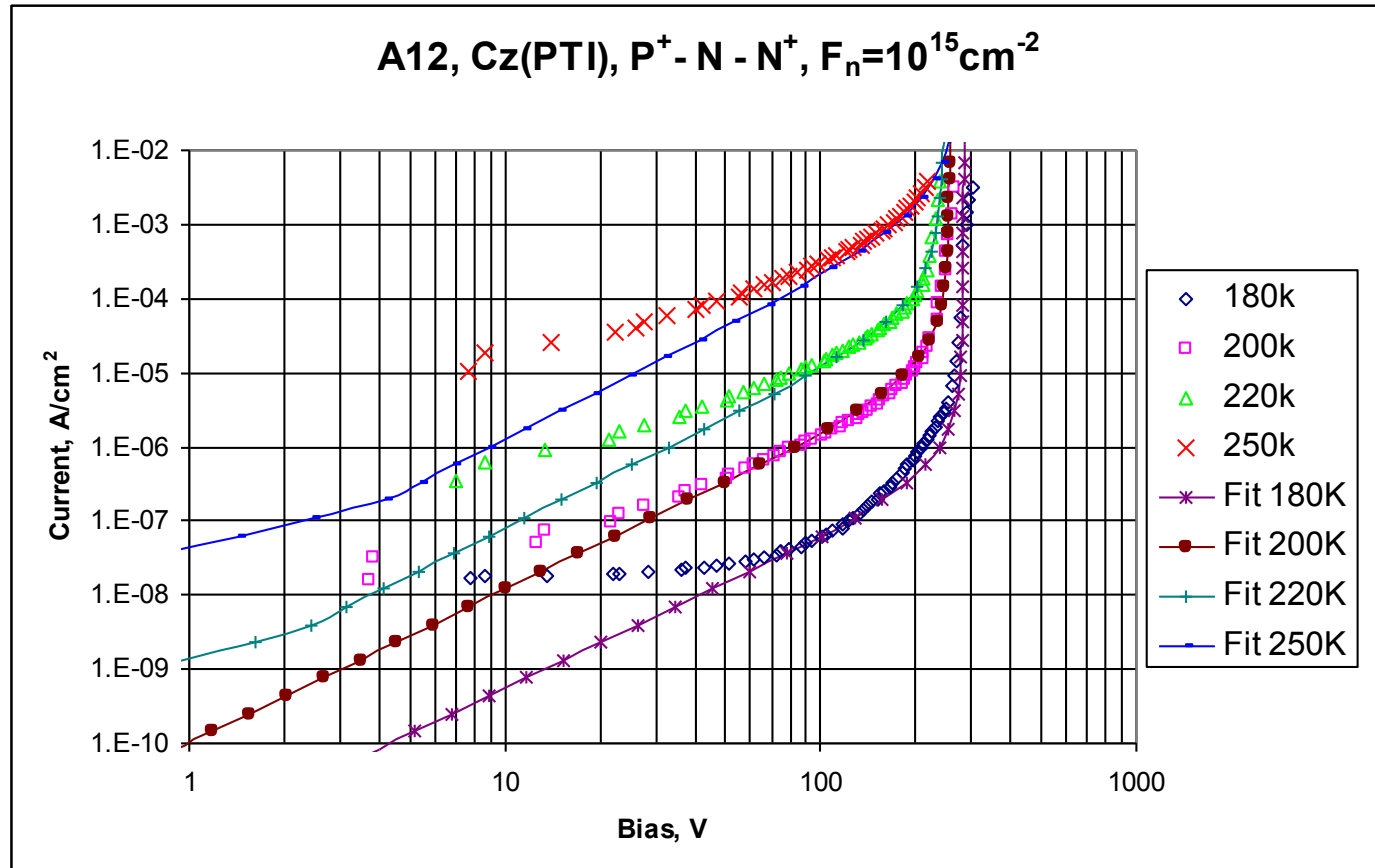


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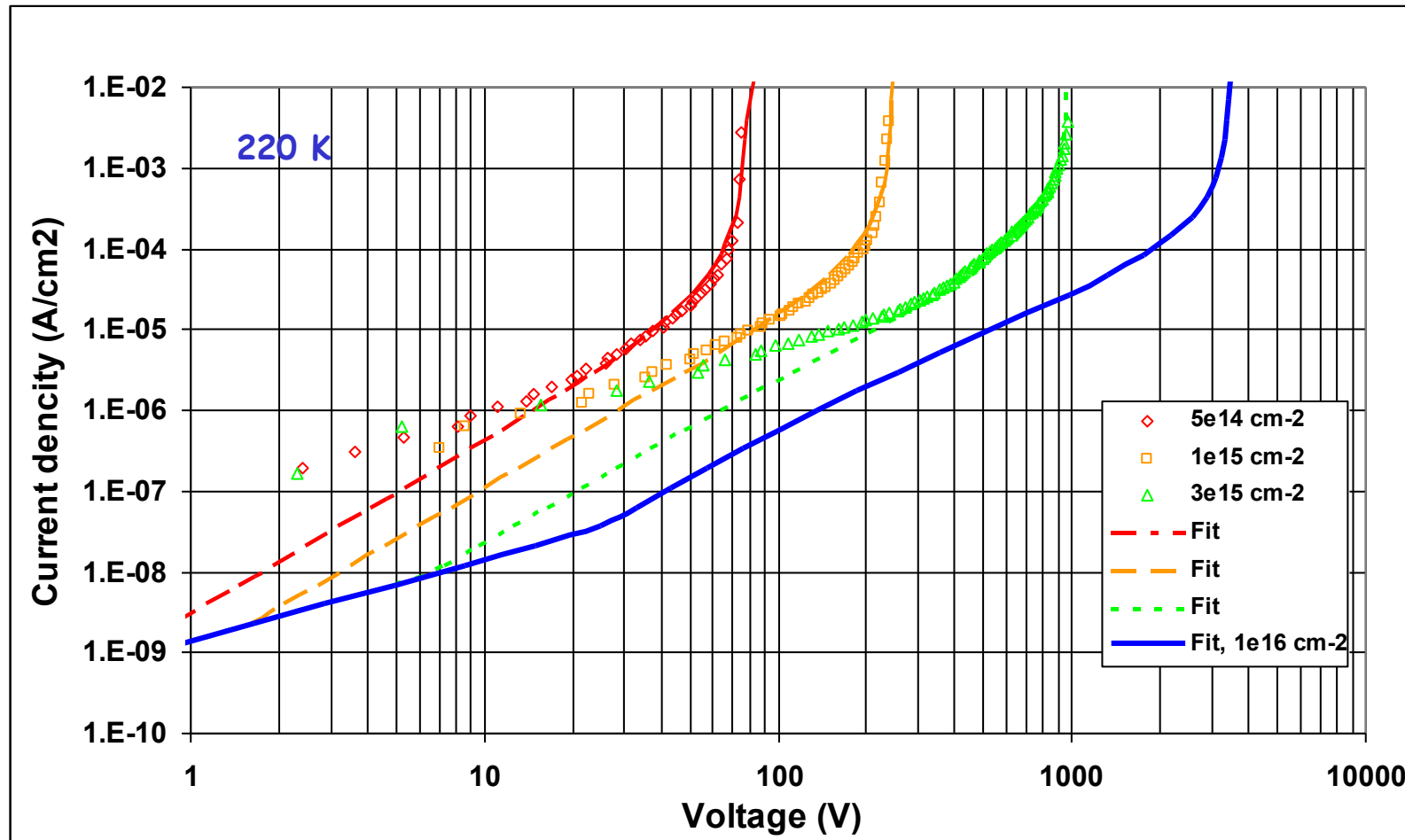
Summary

1. Segmented CID detectors have been modeled to have advantages in having low depletion voltage and trapping
2. CID strip detectors have been beam-tested to be much more rad-hard than the standard ones up to $5 \times 10^{15} n_{eq}/cm^2$
3. Tests (ps-laser, beam) are underway for the application of CID detectors as the beam-loss-monitor for the LHC Upgrade


I-V characteristics of CID



I-V characteristics of CID

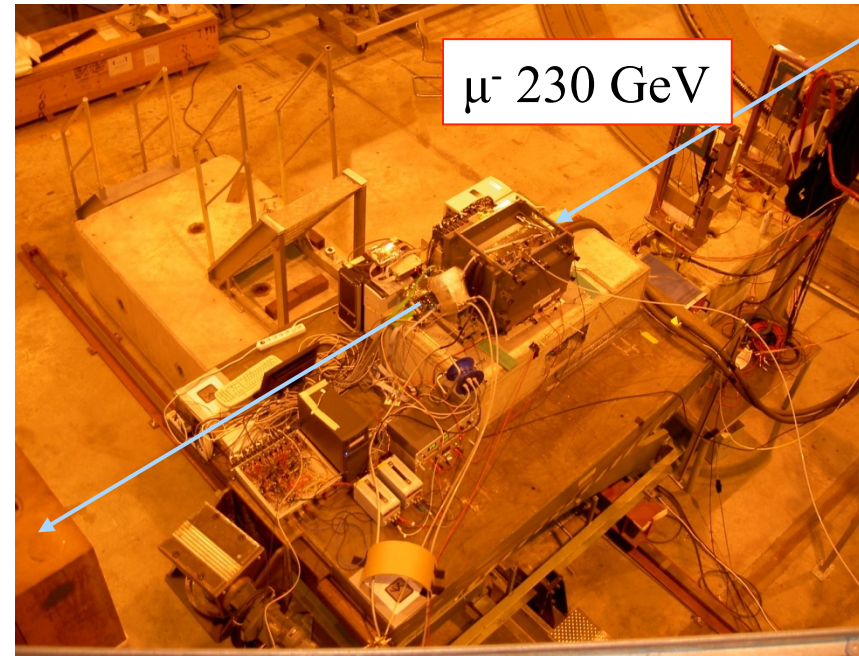


Main advantages CID over standard PN detectors

1. The detectors are always fully depleted
2. The electric field profile does not change with fluence
3. Much lower bias voltage is needed
4. The higher the radiation fluence, the lower the operation current at given bias and temperature
5. The operation bias range increases with fluence
6. No breakdown problem due to self-adjusted electric field by space charge limited current feedback effect
7. Simple detector processing technology (single-sided planar technology)
8. Injection can also be used to deactivate trapping centers --- CCE 

Characterization of CID strip detectors – Segmented detectors

- Test beam with 225 GeV/c muon beam at CERN H2.
- MCz-Si strip detector irradiated $3 \times 10^{15} n_{eq}/cm^2$.
- 768 channels attached to APV25 read-out
- CID detector placed in external cold box capable to cool down to $-54^\circ C$ while module is operational.
- Data acquisition with modified XDAQ. Analysis with CMSSW.



- 8 reference planes.
- Resolution $\sim 4\mu m$.
- About 25000 events in 20min.